Features

- Fast Read Access Time 90 ns
- Low Power CMOS Operation
 - 100 µA Max Standby
- 40 mA Max Active at 5 MHz
- JEDEC Standard Packages
 - 32-lead PLCC
 - 32-lead PDIP
 - 32-lead TSOP
- 5V \pm 10% Supply
- High-Reliability CMOS Technology
 - 2,000V ESD Protection
 - 200 mA Latchup Immunity
- Rapid Programming Algorithm 50 µs/Byte (Typical)
- CMOS and TTL Compatible Inputs and Outputs
- Integrated Product Identification Code
- Industrial Temperature Range
- Green (Pb/Halide-free) Packaging Option

1. Description

The AT27C080 chip is a low-power, high-performance 8,388,608-bit one-time programmable read only memory (OTP EPROM) organized as 1M by 8 bits. The AT27C080 requires only one 5V power supply in normal read mode operation. Any byte can be accessed in less than 90 ns, eliminating the need for speed reducing WAIT states on high-performance microprocessor systems.

Atmel's scaled CMOS technology provides low active power consumption and fast programming. Power consumption is typically 10 mA in active mode and less than 10 μ A in standby mode.

The AT27C080 is available in a choice of packages, including; one-time programmable (OTP) plastic PLCC, PDIP and TSOP. All devices feature two-line control (\overline{CE} , \overline{OE}) to give designers the flexibility to prevent bus contention.

With high density 1-Mbyte storage capability, the AT27C080 allows firmware to be stored reliably and to be accessed by the system without the delays of mass storage media.

Atmel's AT27C080 has additional features to ensure high quality and efficient production use. The Rapid Programming Algorithm reduces the time required to program the part and guarantees reliable programming. Programming time is typically only 50 μ s/byte. The Integrated Product Identification Code electronically identifies the device and manufacturer. This feature is used by industry standard programming equipment to select the proper programming algorithms and voltages.



8-Megabit (1M x 8) OTP EPROM

AT27C080

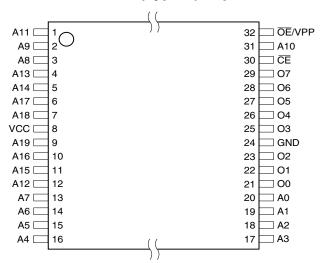






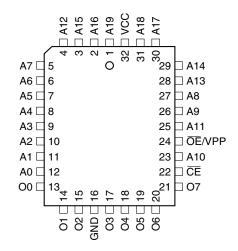
2. Pin Configurations

Pin Name	Function
A0 - A19	Addresses
00 - 07	Outputs
CE	Chip Enable
0E/VPP	Output Enable/Program Supply



2.1 32-lead TSOP (Type 1) Top View

2.3 32-lead PLCC Top View



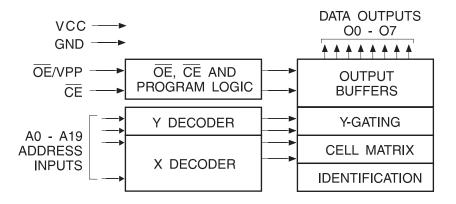
2.2 32-lead PDIP Top View

	\bigcirc		1
A19 🗆	1	32	□ vcc
A16 🗆	2	31	🗆 A18
A15 🗆	3	30	🗆 A17
A12 🗆	4	29	🗆 A14
A7 🗆	5	28	🗆 A13
A6 🗆	6	27	🗆 A8
A5 🗆	7	26	🗆 A9
A4 🗆	8	25	🗆 A11
АЗ 🗆	9	24	
A2 🗆	10	23	🗆 A10
A1 🗆	11	22	
A0 🗆	12	21	07
O0 🗆	13	20	06
O1 🗆	14	19	D 05
O2 🗆	15	18	04
GND 🗆	16	17	D O3
			J

3. System Considerations

Switching between active and standby conditions via the Chip Enable pin may produce transient voltage excursions. Unless accommodated by the system design, these transients may exceed datasheet limits, resulting in device non-conformance. At a minimum, a 0.1 μ F high frequency, low inherent inductance, ceramic capacitor should be utilized for each device. This capacitor should be connected between the V_{CC} and Ground terminals of the device, as close to the device as possible. Additionally, to stabilize the supply voltage level on printed circuit boards with large EPROM arrays, a 4.7 μ F bulk electrolytic capacitor should be utilized, again connected between the V_{CC} and Ground terminals. This capacitor should be positioned as close as possible to the point where the power supply is connected to the array.

4. Block Diagram



5. Absolute Maximum Ratings*

Temperature Under Bias	o +125°C
Storage Temperature	o +150°C
Voltage on Any Pin with Respect to Ground2.0V to	o +7.0V ⁽¹⁾
Voltage on A9 with Respect to Ground2.0V to	+14.0V ⁽¹⁾
V _{PP} Supply Voltage with Respect to Ground2.0V to	+14.0V ⁽¹⁾
Integrated UV Erase Dose	/•sec/cm ²

*NOTICE: Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

Note: 1. Minimum voltage is -0.6V DC which may undershoot to -2.0V for pulses of less than 20 ns. Maximum output pin voltage is V_{CC} + 0.75V DC which may overshoot to +7.0V for pulses of less than 20 ns.





6. Operating Modes

Mode/Pin	CE	OE/V _{PP}	Ai	Outputs
Read	V _{IL}	V _{IL}	Ai	D _{OUT}
Output Disable	X	V _{IH}	X ⁽¹⁾	High Z
Standby	V _{IH}	Х	Х	High Z
Rapid Program ⁽²⁾	V _{IL}	V _{PP}	Ai	D _{IN}
PGM Verify	V _{IL}	V _{IL}	Ai	D _{OUT}
PGM Inhibit	V _{IH}	V _{PP}	Х	High Z
Product Identification ⁽⁴⁾	V _{IL}	V _{IL}	$A9 = V_{H}^{(3)}$ $A0 = V_{IH} \text{ or } V_{IL}$ $A1 - A19 = V_{IL}$	Identification Code

Notes: 1. X can be V_{IL} or $V_{IH.}$

2. Refer to Programming Characteristics.

- 3. $V_{H} = 12.0 \pm 0.5 V.$
- Two identifier bytes may be selected. All Ai inputs are held low (V_{IL}), except A9 which is set to V_H and A0 which is toggled low (V_{IL}) to select the Manufacturer's Identification byte and high (V_{IH}) to select the Device Code byte.

7. DC and AC Operating Conditions for Read Operation

	AT27C080-90
Industrial Operating Temperature (Case)	-40° C - 85° C
V _{CC} Power Supply	$5V \pm 10\%$

8. DC and Operating Characteristics for Read Operation

Symbol	Parameter	Condition	Min	Max	Units
ILI	Input Load Current	$V_{IN} = 0V$ to V_{CC} (Com., Ind.)		±1.0	μA
I _{LO}	Output Leakage Current	$V_{OUT} = 0V$ to V_{CC} (Com., Ind.)		±5.0	μA
	V (1) Oto polity Coursept	I_{SB1} (CMOS), $\overline{CE} = V_{CC} \pm 0.3V$		100	μA
I _{SB}	V _{CC} ⁽¹⁾ Standby Current	I_{SB2} (TTL), \overline{CE} = 2.0 to V_{CC} + 0.5V		1.0	mA
I _{CC}	V _{CC} Active Current	$f = 5 \text{ MHz}, I_{OUT} = 0 \text{ mA}, \overline{CE} = V_{IL}$		40	mA
V _{IL}	Input Low Voltage		-0.6	0.8	V
V _{IH}	Input High Voltage		2.0	V _{CC} + 0.5	V
V _{OL}	Output Low Voltage	I _{OL} = 2.1 mA		0.4	V
V _{OH}	Output High Voltage	I _{OH} = -400 μA	2.4		V

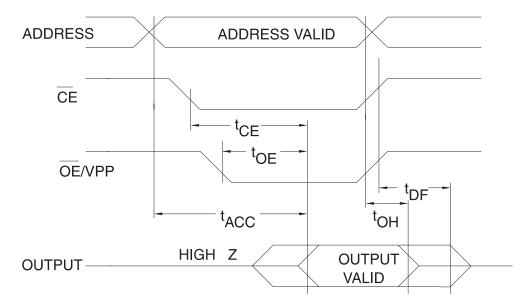
Note: 1. V_{CC} must be applied simultaneously or before \overline{OE}/V_{PP} , and removed simultaneously or after \overline{OE}/V_{PP} .

4

9. AC Characteristics for Read Operation

			AT27C080-90		
Symbol	Parameter	Condition	Min	Max	Units
t _{ACC} ⁽⁴⁾	Address to Output Delay	$\overline{CE} = \overline{OE}/V_{PP}$ $= V_{IL}$		90	ns
t _{CE} ⁽³⁾	CE to Output Delay	$\overline{OE} = V_{IL}$		90	ns
t _{OE} ⁽³⁾⁽⁴⁾	OE to Output Delay	$\overline{CE} = V_{IL}$		20	ns
t _{DF} ⁽²⁾⁽⁵⁾	$\overline{\text{OE}}$ or $\overline{\text{CE}}$ High to Output Float, whichever occur		30	ns	
t _{OH}	Output Hold from Address, \overline{CE} or \overline{OE}/V_{PP} which	0		ns	

10. AC Waveforms for Read Operation⁽¹⁾



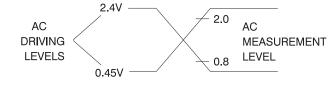
Notes: 1. Timing measurement references are 0.8V and 2.0V. Input AC drive levels are 0.45V and 2.4V, unless otherwise specified.

- 2. t_{DF} is specified form \overline{OE}/V_{PP} or \overline{CE} , whichever occurs first. Output float is defined as the point when data is no longer driven.
- 3. \overline{OE}/V_{PP} may be delayed up to t_{CE} t_{OE} after the falling edge of \overline{CE} without impact on t_{CE} .
- OE/V_{PP} may be delayed up to t_{ACC}- t_{OE} after the address is valid without impact on t_{ACC}.
- 5. This parameter is only sampled and is not 100% tested.



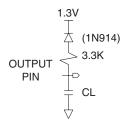


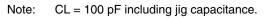
11. Input Test Waveform and Measurement Levels



t_R, t_F < 20 ns (10% to 90%)

12. Output Test Load





13. Pin Capacitance

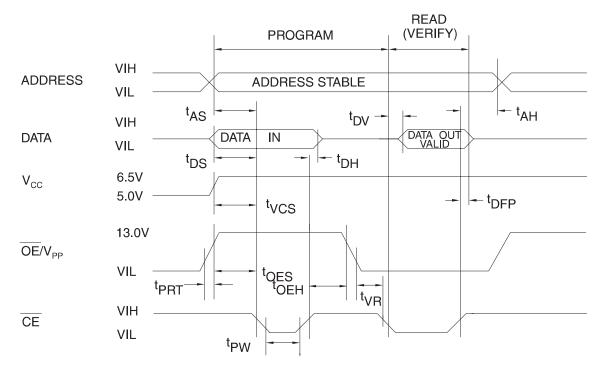
f = 1 MHz, T = $25^{\circ} C^{(1)}$

Symbol	Тур	Мах	Units	Conditions
C _{IN}	4	8	pF	$V_{IN} = 0V$
C _{OUT}	8	12	pF	$V_{OUT} = 0V$

Note: 1. Typical values for nominal supply voltage. This parameter is only sampled and is not 100% tested.

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14. Programming Waveforms



- Notes: 1. The Input Timing reference is 0.8V for $\rm V_{IL}$ and 2.0V for $\rm V_{IH}.$
 - 2. t_{OE} and t_{DFP} are characteristics of the device but must be accommodated by the programmer.





15. DC Programming Characteristics

 $T_A = 25 \pm 5^{\circ}C, V_{CC} = 6.5 \pm 0.25V, \overline{OE}/V_{PP} = 13.0 \pm 0.25V$

			Lir	Limits	
Symbol	Parameter	Test Conditions	Min	Max	Units
I _{LI}	Input Load Current	$V_{IN} = V_{IL}, V_{IH}$		±10	μA
V _{IL}	Input Low Level		-0.6	0.8	V
V _{IH}	Input High Level		2.0	V _{cc} + 1.0	V
V _{OL}	Output Low Voltage	I _{OL} = 2.1 mA		0.4	V
V _{OH}	Output High Voltage	I _{OH} = -400 μA	2.4		V
I _{CC2}	V _{CC} Supply Current (Program and Verify)			40	mA
I _{PP2}	OE/V _{PP} Supply Current	$\overline{CE} = V_{IL}$		25	mA
V _{ID}	A9 Product Identification Voltage		11.5	12.5	V

16. AC Programming Characteristics

 $T_A = 25 \pm 5^{\circ}C$, $V_{CC} = 6.5 \pm 0.25V$, $\overline{OE}/V_{PP} = 13.0 \pm 0.25V$

			Liı	nits	
Symbol	Parameter	Test Conditions ⁽¹⁾	Min	Max	Units
t _{AS}	Address Setup Time		2.0		μs
t _{OES}	OE/V _{PP} Setup Time		2.0		μs
t _{OEH}	OE/V _{PP} Hold Time	Input Rise and Fall Times:	2.0		μs
t _{DS}	Data SetupTime	(10% to 90%) 20 ns	2.0		μs
t _{AH}	Address Hold Time	Input Pulse Levels:	0.0		μs
t _{DH}	Data Hold Time	0.45V to 2.4V	2.0		μs
t _{DFP}	CE High to Output Float Delay ⁽²⁾		0.0	130	ns
t _{VCS}	V _{CC} Setup Time	Input Timing Reference Level: 0.8V to 2.0V	2.0		μs
t _{PW}	CE Program Pulse Width ⁽³⁾		47.5	52.5	μs
t _{DV}	Data Valid from CE	Output Timing Reference Level:		1.0	μs
t _{vR}	OE/V _{PP} Recovery Time	0.8V to 2.0V	2.0		ns
t _{PRT}	OE/V _{PP} Pulse Rise Time During Programming		50		ns

Notes: 1. V_{CC} must be applied simultaneously or before \overline{OE}/V_{PP} and removed simultaneously or after \overline{OE}/V_{PP}

2. This parameter is only sampled and is not 100% tested. Output Float is defined as the point where data is no longer driven – see timing diagram.

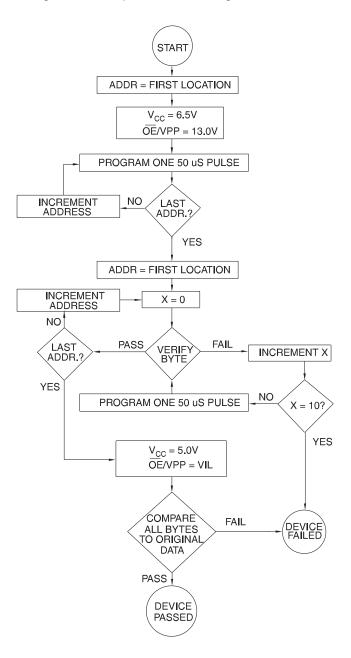
3. Program Pulse width tolerance is 50 μs ± 5%.

17. Atmel's AT27C080 Integrated Product Identification Code

	Pins									
Codes	A0	07	O 6	O5	04	O3	02	01	00	Hex Data
Manufacturer	0	0	0	0	1	1	1	1	0	1E
Device Type	1	1	0	0	0	1	0	1	0	8A

18. Rapid Programming Algorithm

A 50 μ s \overline{CE} pulse width is used to program. The address is set to the first location. V_{CC} is raised to 6.5V and \overline{OE}/V_{PP} is raised to 13.0V. Each address is first programmed with one 50 μ s \overline{CE} pulse without verification. Then a verification reprogramming loop is executed for each address. In the event a byte fails to pass verification, up to 10 successive 50 μ s pulses are applied with a verification after each pulse. If the byte fails to verify after 10 pulses have been applied, the part is considered failed. After the byte verifies properly, the next address is selected until all have been checked. \overline{OE}/V_{PP} is then lowered to V_{IL} and V_{CC} to 5.0V. All bytes are read again and compared with the original data to determine if the device passes or fails.







19. Ordering Information

19.1 Standard Package

t _{ACC}	I _{CC}	(mA)			
(ns)	Active	Active Standby Ordering Code Package		Package	Operation Range
90	40	0.1	AT27C080-90JI AT27C080-90PI AT27C080-90TI	32J 32P6 32T	Industrial (-40° C to 85° C)
Note:	Not reco	ommended for	new designs. Use Green	package option.	

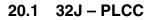
Not recommended for new designs. Use Green package option.

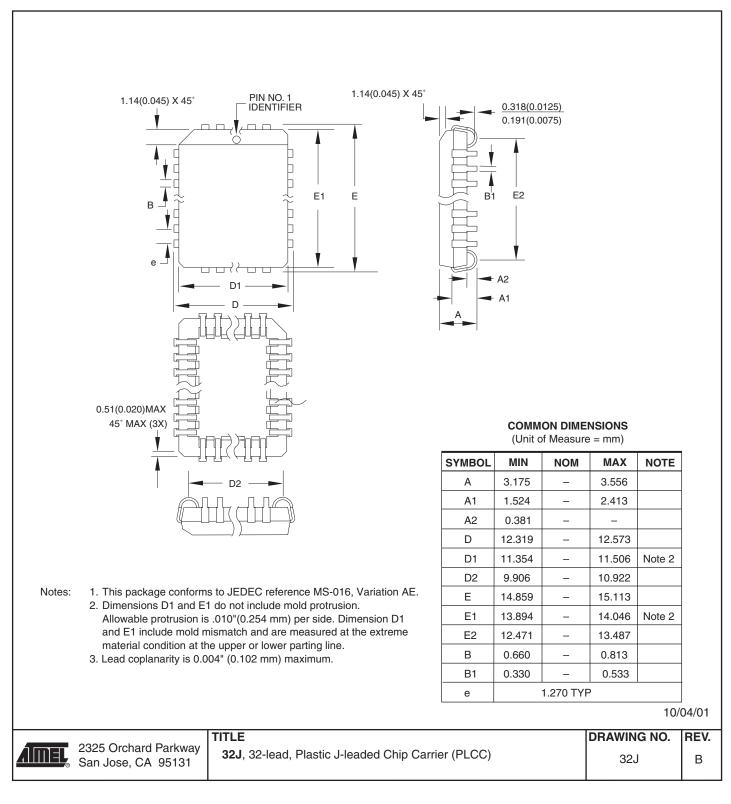
19.2 Green Package (Pb/Halide-free)

t _{ACC}	I _{CC} (mA)				
(ns)	Active	Standby	Ordering Code	Package	Operation Range
90	40	0.1	AT27C080-90JU AT27C080-90PU AT27C080-90TU	32J 32P6 32T	Industrial (-40° C to 85° C)

Package Type				
32J	32-lead, Plastic J-leaded Chip Carrier (PLCC)			
32P6	32-lead, 0.600" Wide, Plastic Dual Inline Package (PDIP)			
32T	32-lead, Plastic Thin Small Outline Package (TSOP)			

20. Package Information

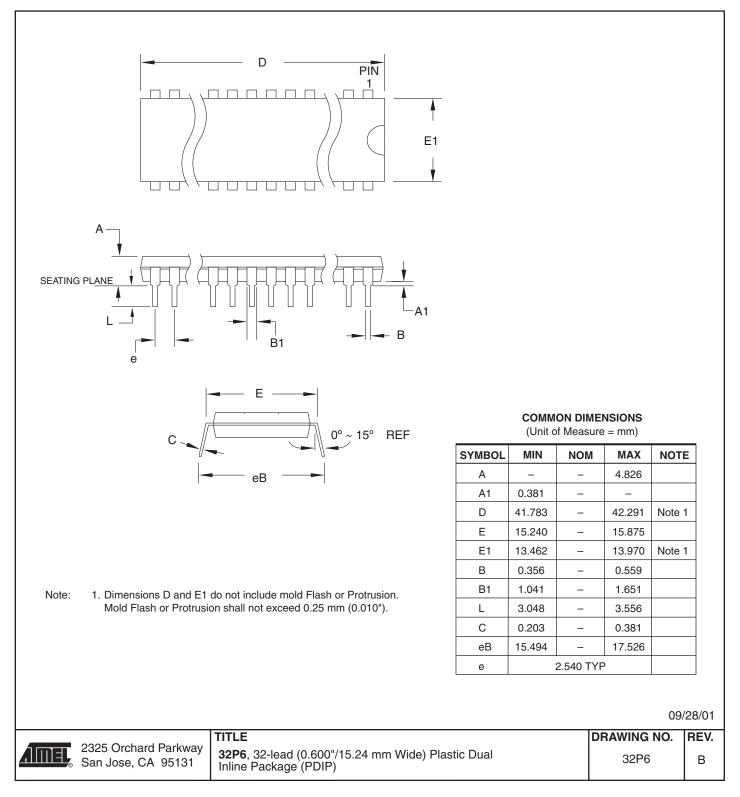




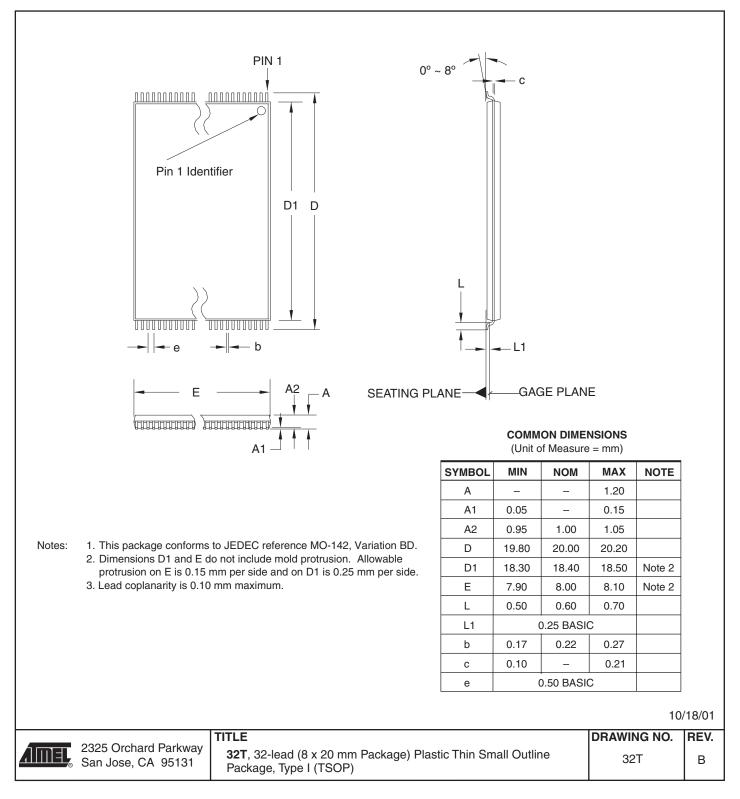




20.2 32P6 - PDIP



20.3 32T – TSOP







Headquarters

Atmel Corporation 2325 Orchard Parkway San Jose, CA 95131 USA Tel: 1(408) 441-0311 Fax: 1(408) 487-2600

International

Atmel Asia Room 1219 Chinachem Golden Plaza 77 Mody Road Tsimshatsui East Kowloon Hong Kong Tel: (852) 2721-9778 Fax: (852) 2722-1369 Atmel Europe Le Krebs 8, Rue Jean-Pierre Timbaud BP 309 78054 Saint-Quentin-en-Yvelines Cedex France Tel: (33) 1-30-60-70-00 Fax: (33) 1-30-60-71-11

Atmel Japan

9F, Tonetsu Shinkawa Bldg. 1-24-8 Shinkawa Chuo-ku, Tokyo 104-0033 Japan Tel: (81) 3-3523-3551 Fax: (81) 3-3523-7581

Product Contact

Web Site www.atmel.com Technical Support eprom@atmel.com Sales Contact www.atmel.com/contacts

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